SGUS039 - AUGUST 2002

- Controlled Baseline

   One Assembly/Test Site, One Fabrication Site
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product Change Notification
- Qualification Pedigree<sup>†</sup>
- Operating Temperature Ranges:
   Military (M) –55°C to 125°C
- High-Performance Floating-Point Digital Signal Processor (DSP):
  - SM320LC31-40EP (3.3 V)
     50-ns Instruction Cycle Time
     220 MOPS, 40 MFLOPS, 20 MIPS
- 32-Bit High-Performance CPU
- 16-/32-Bit Integer and 32-/40-Bit Floating-Point Operations
- 32-Bit Instruction and Data Words, 24-Bit Addresses
- Two 1K Word × 32-Bit Single-Cycle Dual-Access On-Chip RAM Blocks
- Boot-Program Loader
- 64-Word × 32-Bit Instruction Cache
- Eight Extended-Precision Registers
- Two Address Generators With Eight Auxiliary Registers and Two Auxiliary Register Arithmetic Units (ARAUs)
- Two Low-Power Modes

- On-Chip Memory-Mapped Peripherals:
   One Serial Port Supporting
  - 8-/16-/24-/32-Bit Transfers
  - Two 32-Bit Timers
  - One-Channel Direct Memory Access (DMA) Coprocessor for Concurrent I/O and CPU Operation
- Fabricated Using Enhanced Performance Implanted CMOS (EPIC<sup>™</sup>) Technology by Texas Instruments (TI)
- Two- and Three-Operand Instructions
- 40/32-Bit Floating-Point/Integer Multiplier and Arithmetic Logic Unit (ALU)
- Parallel ALU and Multiplier Execution in a Single Cycle
- Block-Repeat Capability
- Zero-Overhead Loops With Single-Cycle Branches
- Conditional Calls and Returns
- Interlocked Instructions for Multiprocessing Support
- Bus-Control Registers Configure
   Strobe-Control Wait-State Generation
- Validated Ada Compiler
- Integer, Floating-Point, and Logical Operations
- 32-Bit Barrel Shifter
- One 32-Bit Data Bus (24-Bit Address)
  - Packaging
    - 132-Lead Plastic Quad Flatpack (PQ Suffix)

#### description

The SM320LC31-EP digital signal processor (DSP) is a 32-bit, floating-point processor manufactured in 0.6-µm triple-level-metal CMOS technology. The device is part of the SMJ320C3x generation of DSPs from Texas Instruments.

The SM320LC31-EP internal busing and special digital-signal-processing instruction set have the speed and flexibility to execute up to 60 MFLOPS. The SM320LC31-EP optimizes speed by implementing functions in hardware that other processors implement through software or microcode. This hardware-intensive approach provides performance previously unavailable on a single chip.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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<sup>†</sup> Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

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SGUS039 - AUGUST 2002

#### description (continued)

The SM320LC31-EP can perform parallel multiply and ALU operations on integer or floating-point data in a single cycle. Each processor also possesses a general-purpose register file, a program cache, dedicated ARAUs, internal dual-access memories, one DMA channel supporting concurrent I/O, and a short machine-cycle time. High performance and ease of use are results of these features.

General-purpose applications are greatly enhanced by the large address space, multiprocessor interface, internally and externally generated wait states, one external interface port, two timers, one serial port, and multiple-interrupt structure. The SM320LC31-EP supports a wide variety of system applications from host processor to dedicated coprocessor.

High-level-language support is easily implemented through a register-based architecture, large address space, powerful addressing modes, flexible instruction set, and well-supported floating-point arithmetic.

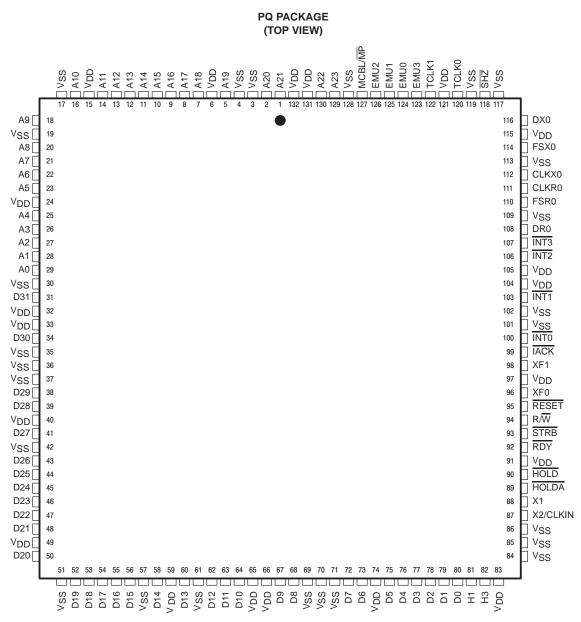
For additional information when designing for cold temperature operation, please see Texas Instruments application report 320C3x, 320C4x and 320MCM42x Power-up Sensitivity at Cold Temperature, literature number SGUA001.



SGUS039 - AUGUST 2002

#### SM320LC31-EP pinout (top view)

The SM320LC31-EP device is packaged in a132-pin plastic quad flatpack (PQ Suffix). The full part number is SM320LC31PQM40EP.





SGUS039 - AUGUST 2002

#### Terminal Assignments (PQ Package)

PI	N	PI	N	Р	IN	Р	IN
NUMBER	NAME	NUMBER	NAME	NUMBER	NAME	NUMBER	NAME
29	A0	64	D10	103	INT1	30	V <sub>SSL</sub> †
28	A1	63	D11	106	INT2	35	V <sub>SSL</sub> †
27	A2	62	D12	107	INT3	36	DVSS
26	A3	60	D13	127	MCBL/MP	37	IVss†
25	A4	58	D14	92	R/W	42	DVSS
23	A5	56	D15	95	RDY	51	CV <sub>SS</sub> †
22	A6	55	D16	94	RESET	57	IVss†
21	A7	54	D17	118	SHZ	61	DVSS
20	A8	53	D18	93	STRB	69	V <sub>SSL</sub> †
18	A9	52	D19	120	TCLK0	70	V <sub>SSL</sub> †
16	A10	50	D20			71	DVSS
14	A11	48	D21			84	CV <sub>SS</sub> †
13	A12	47	D22	6	AV <sub>DD</sub> ‡	85	IVSS†
12	A13	46	D23	15	AV <sub>DD</sub> ‡	86	DVSS
11	A14	45	D24	24	V <sub>DDL</sub>	101	V <sub>SSL</sub> †
10	A15	44	D25	32	V <sub>DDL</sub>	102	cv <sub>ss</sub> †
9	A16	43	D26	33	dv <sub>dd</sub> ‡	109	IVSS <sup>†</sup>
8	A17	41	D27	40	dv <sub>dd</sub> ‡	113	V <sub>SUBS</sub> §
7	A18	39	D28	49	dv <sub>dd</sub> ‡	117	DVSS
5	A19	38	D29	59	VDDL	119	CV <sub>SS</sub> †
2	A20	34	D30	65	V <sub>DDL</sub>	128	X1
1	A21	31	D31	66	dv <sub>dd</sub> ‡	88	X2/CLKIN
130	A22	108	DR0	74	dv <sub>dd</sub> ‡	87	XF0
129	A23	116	DX0	83	cv <sub>DD</sub> ‡	96	XF1
111	CLKR0	124	EMU0	91	CV <sub>DD</sub> ‡	98	No Connec
112	CLKX0	125	EMU1	97	V <sub>DDL</sub>		
80	D0	126	EMU2	104	V <sub>DDL</sub>		
79	D1	123	EMU3	105	PV <sub>DD</sub> ‡		
78	D2	110	FSR0	115	PV <sub>DD</sub> ‡		
77	D3	114	FSX0	121	V <sub>DDL</sub>		
76	D4	81	HOLD	131	V <sub>DDL</sub>		
75	D5	82	HOLDA	132	V <sub>SSL</sub> †		
73	D6	90	H1	3	DVSS		
72	D7	89	H3	4	cv <sub>ss</sub> †		
68	D8	99	IACK	17	DVSS		
67	D9	100	<b>INTO</b>	19	CV <sub>SS</sub> †		

 $^\dagger$  CV<sub>SS</sub>, V<sub>SSL</sub>, and IV<sub>SS</sub> are on the same plane.  $^\ddagger$  AV<sub>DD</sub>, DV<sub>DD</sub>, CV<sub>DD</sub>, and PV<sub>DD</sub> are on the same plane.  $^\$$  V<sub>SUBS</sub> connects to die metallization. Tie this pin to clean ground.



SGUS039 - AUGUST 2002

#### **Terminal Functions**

		TYPE <sup>†</sup>	DESCRIPTION	CC		-
NAME	QTY			SIGN/	L IS Z	
		-	PRIMARY-BUS INTERFACE			
D31-D0	32	I/O/Z	32-bit data port	S	Н	R
A23-A0	24	O/Z	24-bit address port	S	Н	R
R/W	1	O/Z	Read/write. $R/\overline{W}$ is high when a read is performed and low when a write is performed over the parallel interface.	S	Н	R
STRB	1	O/Z	External-access strobe	S	Н	
RDY	1	I	Ready. RDY indicates that the external device is prepared for a transaction completion.			
HOLD	1	I	Hold. When $\overline{\text{HOLD}}$ is a logic low, any ongoing transaction is completed. A23–A0, D31–D0, $\overline{\text{STRB}}$ , and $R/\overline{W}$ are placed in the high-impedance state and all transactions over the primary-bus interface are held until HOLD becomes a logic high or until the NOHOLD bit of the primary-bus-control register is set.			
HOLDA	1	O/Z	Hold acknowledge. HOLDA is generated in response to a logic low on HOLD. HOLDA indicates that A23–A0, D31–D0, STRB, and $R/W$ are in the high-impedance state and that all transactions over the bus are held. HOLDA is high in response to a logic high of HOLD or the NOHOLD bit of the primary-bus-control register is set.	S		
		-	CONTROL SIGNALS			
RESET	1	I	Reset. When RESET is a logic low, the device is in the reset condition. When RESET becomes a logic high, execution begins from the location specified by the reset vector.			
INT3-INT0	4	I	External interrupts			
IACK	1	O/Z	Interrupt acknowledge. IACK is generated by the IACK instruction. IACK can be used to indicate the beginning or the end of an interrupt-service routine.	S		
MCBL/MP	1	I	Microcomputer boot-loader/microprocessor mode-select			
SHZ	1	I	Shutdown high impedance. When active, SHZ shuts down the device and places all pins in the high-impedance state. SHZ is used for board-level testing to ensure that no dual-drive conditions occur. <b>CAUTION:</b> A low on SHZ corrupts the device memory and register contents. Reset the device with SHZ high to restore it to a known operating condition.			
XF1, XF0	2	I/O/Z	External flags. XF1 and XF0 are used as general-purpose I/Os or to support interlocked processor instruction.	S		R
			SERIAL PORT 0 SIGNALS			
CLKR0	1	I/O/Z	Serial port 0 receive clock. CLKR0 is the serial shift clock for the serial port 0 receiver.	S		R
CLKX0	1	I/O/Z	Serial port 0 transmit clock. CLKX0 is the serial shift clock for the serial port 0 transmitter.	S		R
DR0	1	I/O/Z	Data-receive. Serial port 0 receives serial data on DR0.	S		R
DX0	1	I/O/Z	Data-transmit output. Serial port 0 transmits serial data on DX0.	S		R
FSR0	1	I/O/Z	Frame-synchronization pulse for receive. The FSR0 pulse initiates the data-receive process using DR0.	S		R
FSX0	1	I/O/Z	Frame-synchronization pulse for transmit. The FSX0 pulse initiates the data-transmit process using DX0.	S		R
			TIMER SIGNALS			
TCLK0	1	I/O/Z	Timer clock 0. As an input, TCLK0 is used by timer 0 to count external pulses. As an output, TCLK0 outputs pulses generated by timer 0.	S		
TCLK1	1	I/O/Z	Timer clock 1. As an input, TCLK0 is used by timer 1 to count external pulses. As an output, TCLK1 outputs pulses generated by timer 1.	S		

 $^{\dagger}$ I = input, O = output, Z = high-impedance state  $^{\ddagger}$ S = SHZ active, H = HOLD active, R = RESET active



SGUS039 - AUGUST 2002

## **Terminal Functions (Continued)**

TERMINAL NAME QTY		TYPET	DESCRIPTION	CONDITIONS WHEN
			DESCRIPTION	
		•	SUPPLY AND OSCILLATOR SIGNALS	
H1	1	O/Z	External H1 clock. H1 has a period equal to twice CLKIN.	S
H3	1	O/Z	External H3 clock. H3 has a period equal to twice CLKIN.	S
V <sub>DD</sub>	20	I	5-V supply for C31 devices and 3.3-V supply for LC31 devices. All must be connected to a common supply plane.§	
V <sub>SS</sub>	25	I	Ground. All grounds must be connected to a common ground plane.	
X1	1	0	Output from the internal-crystal oscillator. If a crystal is not used, X1 should be left unconnected.	
X2/CLKIN	1	I	Internal-oscillator input from a crystal or a clock	
		-	RESERVED	
EMU2-EMU0	3	I	Reserved for emulation. Use pullup resistors to V <sub>DD</sub>	
EMU3	1	O/Z	Reserved for emulation	S

<sup>†</sup>I = input, O = output, Z = high-impedance state <sup>‡</sup>S = SHZ active, H = HOLD active, R = RESET active

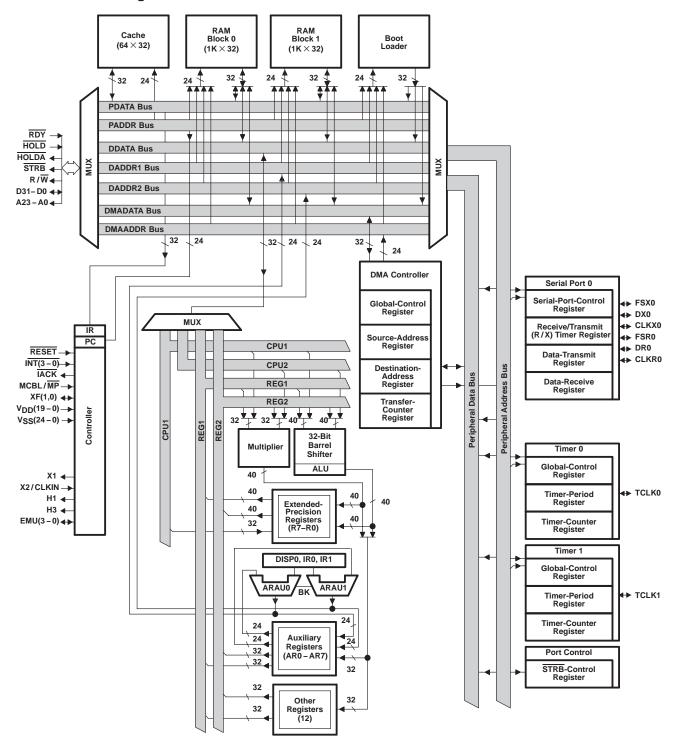
 $\$  Recommended decoupling capacitor value is 0.1  $\mu F.$ 

 $\P$  Follow the connections specified for the reserved pins. Use 18-k $\Omega$ -22-k $\Omega$  pullup resistors for best results. All V<sub>DD</sub> supply pins must be connected to a common supply plane, and all ground pins must be connected to a common ground plane.



SGUS039 - AUGUST 2002

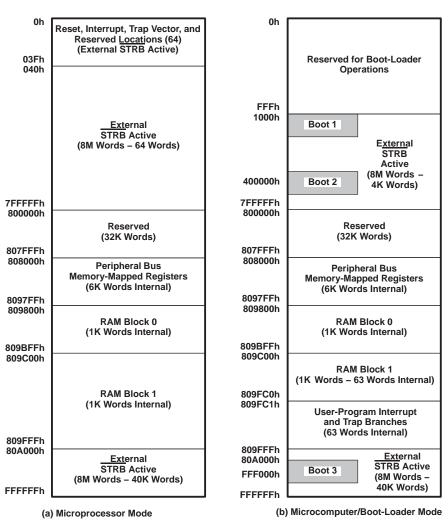
#### functional block diagram





SGUS039 - AUGUST 2002

#### memory map<sup>†</sup>



<sup>†</sup> Figure 1 depicts the memory map for the SMJ320C31. See the *TMS320C3x Users Guide* (literature number SPRU031) for a detailed description of this memory mapping.

Figure 1. SM320C31-EP Memory Map



SGUS039 - AUGUST 2002

#### 00h 809FC1h INT0 Reset 01h INT0 809FC2h INT1 INT1 02h 809FC3h INT2 INT2 03h 809FC4h INT3 04h INT3 809FC5h XINT0 05h XINT0 809FC6h **RINT0 RINT0** 06h 07h 809FC7h Reserved Reserved 08h 809FC8h 09h TINT0 809FC9h TINT0 0Ah 809FCAh TINT1 TINT1 0Bh 809FCBh DINT DINT 0Ch 809FCCh Reserved Reserved 1Fh 809FDFh 809FE0h 20h TRAP 0 TRAP 0 • • . 3Bh TRAP 27 809FFBh TRAP 27 3Ch 809FFCh Reserved Reserved 3Fh 809FFFh (a) Microprocessor Mode (b) Microcomputer/Boot-Loader Mode

memory map (continued)

Figure 2. Reset, Interrupt, and Trap Vector/Branches Memory-Map Locations



SGUS039 - AUGUST 2002

#### memory map (continued)

808000h	DMA Global Control
808004h	DMA Source Address
808006h	DMA Destination Address
808008h	DMA Transfer Counter
808020h	Timer 0 Global Control
808024h	Timer 0 Counter
808028h	Timer 0 Period Register
808030h	Timer 1 Global Control
808034h	Timer 1 Counter
808038h	Timer 1 Period Register
808040h	Serial Global Control
808042h	FSX/DX/CLKX Serial Port Control
808043h	FSR/DR/CLKR Serial Port Control
808044h	Serial R/X Timer Control
808045h	Serial R/X Timer Counter
808046h	Serial R/X Timer Period Register
808048h	Data-Transmit
80804Ch	Data-Receive
808064h	Primary-Bus Control

<sup>†</sup>Shading denotes reserved address locations

Figure 3. Peripheral Bus Memory-Mapped Registers<sup>†</sup>



SGUS039 - AUGUST 2002

#### absolute maximum ratings over specified temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage, V <sub>DD</sub> (see Note 1)
Input voltage, V $_{\rm I}$ $\ldots$ $-0.3$ V to 5 V
Output voltage, V_O $\ldots \ldots \ldots$
Continuous power dissipation (worst case) (see Note 2)
Operating case temperature, T <sub>C</sub>
Storage temperature, T <sub>stg</sub> 65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to V<sub>SS</sub>.

 Actual operating power is less. This value was obtained under specially produced worst-case test conditions for the TMS320C31-33 and the TMS320LC31-40, which are not sustained during normal device operation. These conditions consist of continuous parallel writes of a checkerboard pattern to both primary and extension buses at the maximum rate possible. See normal (I<sub>CC</sub>) current specification in the electrical characteristics table and also read *Calculation of TMS320C30 Power Dissipation Application Report* (literature number SPRA020).

#### recommended operating conditions (see Note 3)

		MIN	NOM	MAX	UNIT
V <sub>DD</sub>	Supply voltage (DV <sub>DD</sub> , etc.)	3.13	3.3	3.47	V
VSS	Supply voltage (CV <sub>SS</sub> , etc.)		0		V
	High-level input voltage (except RESET)	1.8		V <sub>DD</sub> + 0.3*	V
VIH	High-level input voltage (RESET)	2.2		V <sub>DD</sub> + 0.3*	V
VIL	Low-level input voltage	- 0.3*		0.6	V
IOH	High-level output current			- 300	μΑ
IOL	Low-level output current			2	mA
ТС	Operating case temperature	-55		125	°C
VTH	High-level input voltage for CLKIN	2.5		V <sub>DD</sub> + 0.3*	V

\* This parameter is not production tested.

NOTE 3: All voltage values are with respect to V<sub>SS</sub>. All input and output voltage levels are TTL-compatible. CLKIN can be driven by a CMOS clock.



SGUS039 - AUGUST 2002

#### electrical characteristics over recommended ranges of supply voltage (unless otherwise noted) (see Note 3)<sup>†</sup>

	PARAMETER	TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
VOH	High-level output voltage	V <sub>DD</sub> = MIN, I <sub>OH</sub> = MAX	2			V
VOL	Low-level output voltage	$V_{DD} = MIN, I_{OH} = MAX$			0.4	V
ΙZ	High-impedance current	$V_{DD} = MAX$	- 20		+ 20	μA
II .	Input current	$V_I = V_{SS}$ to $V_{DD}$	- 10		+ 10	μΑ
I <sub>IP</sub>	Input current (with internal pullup)	Inputs with internal pullups§	- 600		10	μA
ICC	Supply current¶#	$\begin{array}{l} T_{A} = 25^{\circ}C, \\ V_{DD} = MAX \end{array} \qquad \qquad f_{X} = 40 \; MHz$	:	150	300	mA
IDD	Supply current	Standby, IDLE2, Clocks s	hut off	20		μA
~		All inputs except CLKIN			15*	_
Ci	Input capacitance	CLKIN			25	pF
Co	Output capacitance				20*	pF

<sup>†</sup> All input and output voltage levels are TTL compatible.

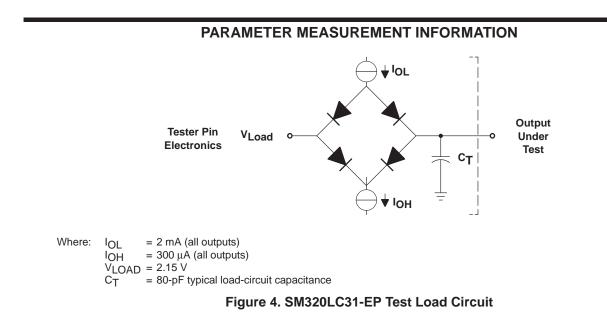
<sup>‡</sup> For LC31, all typical values are at  $V_{DD} = 3.3 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ . § Pins with internal pullup devices: INT3–INT0, MCBL/MP.

I Actual operating current is less than this maximum value. This value was obtained under specially produced worst-case test conditions, which are not sustained during normal device operation. These conditions consist of continuous parallel writes of a checkerboard pattern to both primary and expansion buses at the maximum rate possible. See Calculation of TMS320C30 Power Dissipation Application Report (literature number SPRA020).

 $^{\#}$  f<sub>x</sub> is the input clock frequency.

\* This parameter is not production tested.

NOTE 3: All voltage values are with respect to VSS. All input and output voltage levels are TTL-compatible. CLKIN can be driven by a CMOS clock.





SGUS039 - AUGUST 2002

### PARAMETER MEASUREMENT INFORMATION

#### signal transition levels for LC31 (see Figure 5 and Figure 6)

Outputs are driven to a minimum logic-high level of 2 V and to a maximum logic-low level of 0.4 V. Output transition times are specified as follows:

- For a high-to-low transition on an output signal, the level at which the output is said to be no longer high is 2 V and the level at which the output is said to be low is 1 V.
- For a low-to-high transition, the level at which the output is said to be no longer low is 1 V and the level at which the output is said to be high is 2 V.

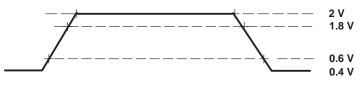


Figure 5. LC31 Output Levels

Transition times for inputs are specified as follows:

- For a high-to-low transition on an input signal, the level at which the input is said to be no longer high is 1.8 V and the level at which the input is said to be low is 0.6 V.
- For a low-to-high transition on an input signal, the level at which the input is said to be no longer low is 0.6 V and the level at which the input is said to be high is 1.8 V.



Figure 6. LC31 Input Levels



SGUS039 - AUGUST 2002

### PARAMETER MEASUREMENT INFORMATION

#### timing parameter symbology

Timing parameter symbols used herein were created in accordance with JEDEC Standard 100-A. In order to shorten the symbols, some of the pin names and other related terminology have been abbreviated as follows, unless otherwise noted:

А	A23-A0	Н	H1 and H3
ASYNCH	Asynchronous reset signals	HOLD	HOLD
С	CLKX0	HOLDA	HOLDA
CI	CLKIN	IACK	IACK
CLKR	CLKR0	INT	INT3-INT0
CONTROL	Control signals	RDY	RDY
D	D31-D0	RW	R/W
DR	DR	RESET	RESET
DX	DX	S	STRB
FS	FSX/R	SCK	CLKX/R
FSX	FSX0	SHZ	SHZ
FSR	FSR0	TCLK	TCLK0, TCLK1, or TCLKx
GPI	General-purpose input	XF	XF0, XF1, or XFx
GPIO	General-purpose input/output; peripheral pin	XFIO	XFx switching from input to output
GPO	General-purpose output		



## timing

Timing specifications apply to the SM320LC31-EP.

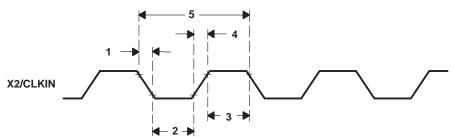
#### X2/CLKIN, H1, and H3 timing

The following table defines the timing parameters for the X2/CLKIN, H1, and H3 interface signals.

#### timing parameters for X2/CLKIN, H1, H3 (see Figure 7, Figure 8, and Figure 9)

NO.			MIN	MAX	UNIT
1	<sup>t</sup> f(CI)	Fall time, CLKIN		5*	ns
2	tw(CIL)	Pulse duration, CLKIN low t <sub>c(CI)</sub> = min	9		ns
3	<sup>t</sup> w(CIH)	Pulse duration, CLKIN high t <sub>C(CI)</sub> = min	9		ns
4	<sup>t</sup> r(CI)	Rise time, CLKIN		5*	ns
5	<sup>t</sup> c(CI)	Cycle time, CLKIN	25	303	ns
6	<sup>t</sup> f(H)	Fall time, H1 and H3		3	ns
7	<sup>t</sup> w(HL)	Pulse duration, H1 and H3 low	P-5†		ns
8	tw(HH)	Pulse duration, H1 and H3 high	P-6†		ns
9	t <sub>r(H)</sub>	Rise time, H1 and H3		3	ns
10	<sup>t</sup> d(HL-HH)	Delay time. from H1 low to H3 high or from H3 low to H1 high	0	4	ns
11	<sup>t</sup> c(H)	Cycle time, H1 and H3	50	606	ns

 $\frac{\dagger P = t_{C(CI)}}{\dagger This parameter is not production tested.}$ 



#### Figure 7. Timing for X2/CLKIN

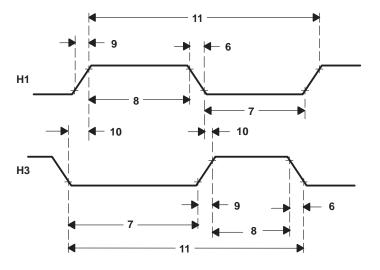


Figure 8. Timing for H1 and H3



SGUS039 - AUGUST 2002



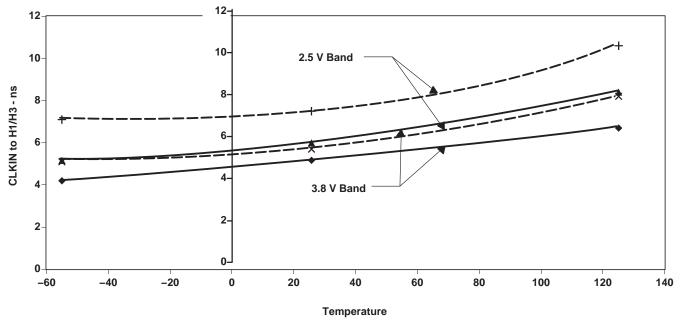


Figure 9. SM320LC31-EP CLKIN to H1/H3 as a Function of Temperature (Typical)



SGUS039 - AUGUST 2002

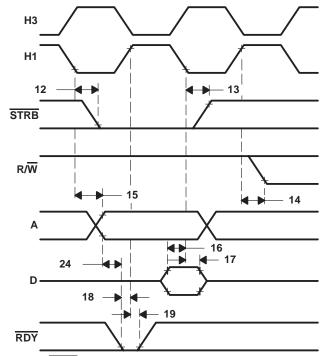
#### memory read/write timing

The following table defines memory read/write timing parameters for STRB.

#### timing parameters for memory (STRB = 0) read/write (see Figure 10 and Figure 11)<sup>†</sup> NO. MIN MAX UNIT 12 Delay time, H1 low to STRB low 0\* 6 ns td(H1L-SL) Delay time, H1 low to STRB high 13 <sup>t</sup>d(H1L-SH) 0\* 6 ns Delay time, H1 high to R/W low (read) 0\* 9 14 td(H1H-RWL)R ns Delay time, H1 low to A valid 0\* 10 15 ns <sup>t</sup>d(H1L-A) 14 16 tsu(D-H1L)R Setup time, D before H1 low (read) ns 17 Hold time, D after H1 low (read) 0 <sup>t</sup>h(H1L-D)R ns Setup time, RDY before H1 high 18 8 tsu(RDY-H1H) ns 19 Hold time, RDY after H1 high 0 ns <sup>t</sup>h(H1H-RDY) Delay time, H1 high to R/W high (write) 20 9 td(H1H-RWH)W ns Valid time, D after H1 low (write) 17 21 <sup>t</sup>v(H1L-D)W ns Hold time, D after H1 high (write) 22 0 <sup>t</sup>h(H1H-D)W ns 23 Delay time, H1 high to A valid on back-to-back write cycles (write) 15 td(H1H-A)W ns Delay time, RDY from A valid 24 7\* ns td(A-RDY)

<sup>†</sup> See Figure 12 for address bus timing variation with load capacitance greater than typical load-circuit capacitance (C<sub>T</sub> = 80 pF).

\* This parameter is not production tested.



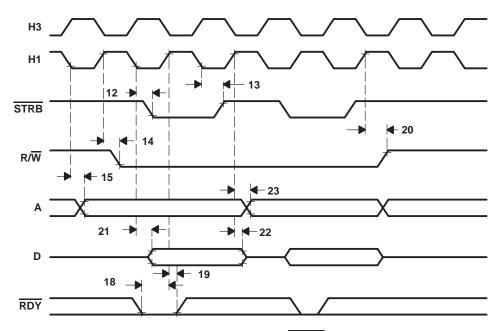
NOTE A: STRB remains low during back-to-back read operations.

Figure 10. Timing for Memory (STRB = 0) Read

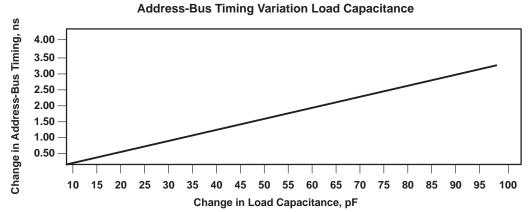


SGUS039 - AUGUST 2002

#### memory read/write timing (continued)







NOTE A: 30 pF/ns slope





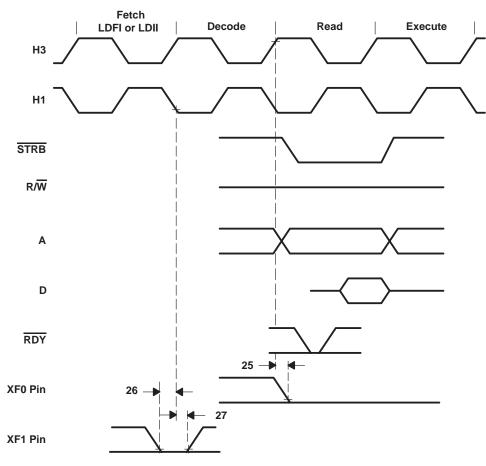
SGUS039 - AUGUST 2002

#### XF0 and XF1 timing when executing LDFI or LDII

The following table defines the timing parameters for XF0 and XF1 during execution of LDFI or LDII.

#### timing for XF0 and XF1 when executing LDFI or LDII (see Figure 13)

NO.		MIN	MAX	UNIT
25	td(H3H-XF0L) Delay time, H3 high to XF0 low		13	ns
26	tsu(XF1-H1L) Setup time, XF1 before H1 low	10		ns
27	th(H1L-XF1) Hold time, XF1 after H1 low	0		ns







SGUS039 - AUGUST 2002

#### XF0 timing when executing STFI and STII<sup>†</sup>

The following table defines the timing parameters for the XF0 pin during execution of STFI or STII.

#### timing for XF0 when executing STFI or STII (see Figure 14)

NO.		MIN	MAX	UNIT
28	t <sub>d(H3H-XF0H)</sub> Delay time, H3 high to XF0 high		13	ns

<sup>†</sup> XF0 is always set high at the beginning of the execute phase of the interlock-store instruction. When no pipeline conflicts occur, the address of the store is also driven at the beginning of the execute phase of the interlock-store instruction. However, if a pipeline conflict prevents the store from executing, the address of the store will not be driven until the store can execute.

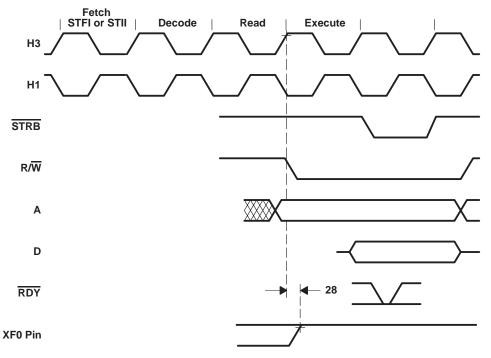


Figure 14. Timing for XF0 When Executing an STFI or STII



SGUS039 - AUGUST 2002

#### XF0 and XF1 timing when executing SIGI

The following table defines the timing parameters for the XF0 and XF1 pins during execution of SIGI.

# timing for XF0 and XF1 when executing SIGI (see Figure 15)

NO.		MIN MAX	UNIT
29	t <sub>d(H3H-XF0L)</sub> Delay time, H3 high to XF0 low	13	ns
30	t <sub>d(H3H-XF0H)</sub> Delay time, H3 high to XF0 high	13	ns
31	t <sub>su(XF1-H1L)</sub> Setup time, XF1 before H1 low	10	ns
32	t <sub>h(H1L-XF1)</sub> Hold time, XF1 after H1 low	0	ns

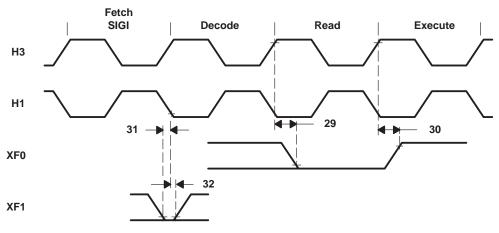


Figure 15. Timing for XF0 and XF1 When Executing SIGI



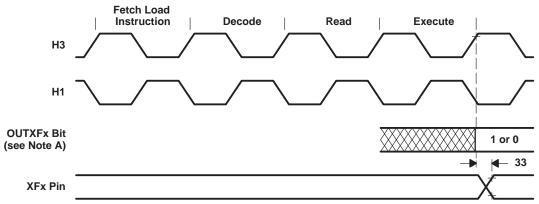
SGUS039 - AUGUST 2002

#### loading when XF is configured as an output

The following table defines the timing parameter for loading the XF register when the XFx pin is configured as an output.

#### timing for loading the XF register when configured as an output pin (see Figure 16)

NO.			MIN	MAX	UNIT
33	t <sub>v(H3H-XF)</sub>	Valid time, H3 high to XFx		13	ns



NOTE A: OUTXFx represents either bit 2 or 6 of the IOF register.

#### Figure 16. Timing for Loading XF Register When Configured as an Output Pin



SGUS039 - AUGUST 2002

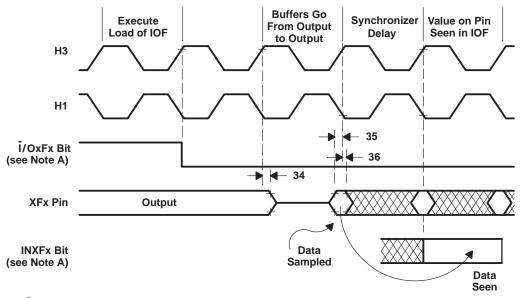
#### changing XFx from an output to an input

The following table defines the timing parameters for changing the XFx pin from an output pin to an input pin.

#### timing of XFx changing from output to input mode (see Figure 17)

NO.		MIN	MAX	UNIT
34	th(H3H-XF) Hold time, XFx after H3 high		13*	ns
35	t <sub>su(XF-H1L)</sub> Setup time, XFx before H1 low	10		ns
36	t <sub>h(H1L-XF)</sub> Hold time, XFx after H1 low	0		ns

\* This parameter is not production tested.



NOTE A: I/OxFx represents either bit 1 or bit 5 of the IOF register, and INXFx represents either bit 3 or bit 7 of the IOF register.

Figure 17. Timing for Change of XFx From Output to Input Mode



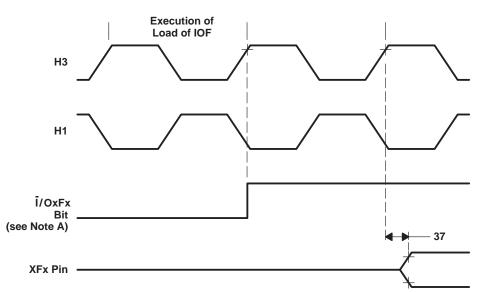
SGUS039 - AUGUST 2002

#### changing XFx from an input to an output

The following table defines the timing parameter for changing the XFx pin from an input pin to an output pin.

#### timing for XFx changing from input to output mode (see Figure 18)

NO.		MIN	MAX	UNIT
37	td(H3H-XFIO) Delay time, H3 high to XFx switching from input to output		17	ns



NOTE A: I/OxFx represents either bit 1 or bit 5 of the IOF register.

#### Figure 18. Timing for Change of XFx From Input to Output Mode

#### reset timing

RESET is an asynchronous input that can be asserted at any time during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 19 occurs; otherwise, an additional delay of one clock cycle is possible.

The asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.

Resetting the device initializes the primary- and expansion-bus control registers to seven software wait states and therefore results in slow external accesses until these registers are initialized.

HOLD is an asynchronous input and can be asserted during reset.



SGUS039 - AUGUST 2002

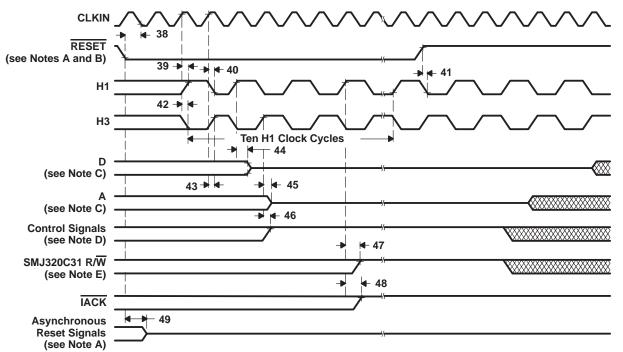
NO.			MIN	MAX	UNIT
38	tsu(RESET-CIL)	Setup time, RESET before CLKIN low	10	P†*	ns
39	<sup>t</sup> d(CLKINH-H1H)	Delay time, CLKIN high to H1 high (see Note 4)	2	14	ns
40	<sup>t</sup> d(CLKINH-H1L)	Delay time, CLKIN high to H1 low (see Note 4)	2	14	ns
41	<sup>t</sup> su(RESETH-H1L)	Setup time, RESET high before H1 low and after ten H1 clock cycles	9		ns
42	td(CLKINH-H3L)	Delay time, CLKIN high to H3 low (see Note 4)	2	14	ns
43	<sup>t</sup> d(CLKINH-H3H)	Delay time, CLKIN high to H3 high (see Note 4)	2	14	ns
44	<sup>t</sup> dis(H1H-DZ)	Disable time, H1 high to D (high impedance)		13*	ns
45	<sup>t</sup> dis(H3H-AZ)	Disable time, H3 high to A (high impedance)		9*	ns
46	<sup>t</sup> d(H3H-CONTROLH)	Delay time, H3 high to control signals high		9*	ns
47	<sup>t</sup> d(H1H-RWH)	Delay time, H1 high to $R/\overline{W}$ high		9*	ns
48	<sup>t</sup> d(H1H-IACKH)	Delay time, H1 high to IACK high		9*	ns
49	<sup>t</sup> dis(RESETL-ASYNCH)	Disable time, RESET low to asynchronous reset signals disabled (high impedance)		21*	ns

### **RESET** timing (see Figure 19)

 $\overline{\dagger} P = t_{C(CI)}$ 

\* This parameter is not production tested.

NOTE 4: See Figure 9 for typical temperature dependence.



NOTES: A. Asynchronous reset signals include XF0/1, CLKX0, DX0, FSX0, CLKR0, DR0, FSR0, and TCLK0/1.

B. RESET is an asynchronous input and can be asserted at any point during a clock cycle. If the specified timings are met, the exact sequence shown occurs; otherwise, an additional delay of one clock cycle is possible.

C. In microprocessor mode, the reset vector is fetched twice, with seven software wait states each time. In microcomputer mode, the reset vector is fetched twice, with no software wait states.

D. Control signals include STRB.

E. The R/ $\overline{W}$  outputs are placed in a high-impedance state during reset and can be provided with a resistive pullup, nominally 18–22 k $\Omega$ , if undesirable spurious writes are caused when these outputs go low.

#### Figure 19. Timing for RESET



SGUS039 - AUGUST 2002

#### interrupt response timing

The following table defines the timing parameters for the INT signals.

### timing for INT3-INT0 response (see Figure 20)

NO.			MIN	MAX	UNIT
50	<sup>t</sup> su(INT-H1L)	Setup time, INT3-INT0 before H1 low	15		ns
51	<sup>t</sup> w(INT)	Pulse duration, interrupt to ensure only one interrupt	Р	2P†*	ns

 $^{\dagger}P = t_{C(H)}$ 

\* This parameter is not production tested.

The interrupt (INT) pins are asynchronous inputs that can be asserted at any time during a clock cycle. The SM320LC31-EP interrupts are level-sensitive, not edge-sensitive. Interrupts are detected on the falling edge of H1. Therefore, interrupts must be set up and held to the falling edge of H1 for proper detection. The CPU and DMA respond to detected interrupts on instruction-fetch boundaries only.

For the processor to recognize only one interrupt on a given input, an interrupt pulse must be set up and held to:

- A minimum of one H1 falling edge
- No more than two H1 falling edges

The SM320LC31-EP can accept an interrupt from the same source every two H1 clock cycles.

If the specified timings are met, the exact sequence shown in Figure 20 occurs; otherwise, an additional delay of one clock cycle is possible.

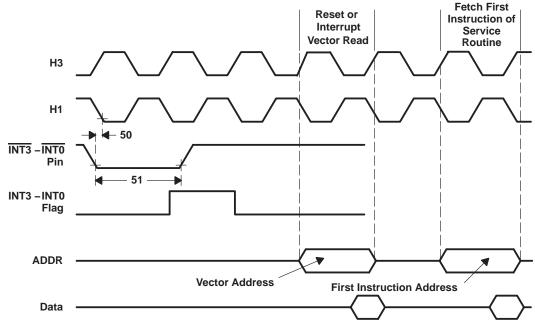


Figure 20. Timing for INT3–INT0 Response



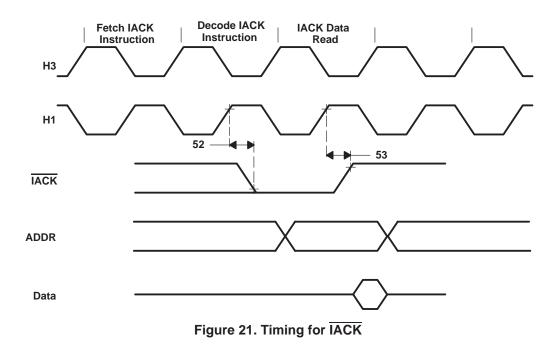
#### interrupt-acknowledge timing

The IACK output goes active on the first half-cycle (HI rising) of the decode phase of the IACK instruction and goes inactive at the first half-cycle (HI rising) of the read phase of the IACK instruction.

timing for IACK (see Note 5 and Figure 21)

NO.		MIN	MAX	UNIT
52	t <sub>d(H1H-IACKL)</sub> Delay time, H1 high to IACK low		9	ns
53	t <sub>d(H1H-IACKH)</sub> Delay time, H1 high to IACK high		9	ns

NOTE 5: IACK goes active on the first half-cycle (H1 rising) of the decode phase of the IACK instruction and goes inactive at the first half-cycle (H1 rising) of the read phase of the IACK instruction. Because of pipeline conflicts, IACK remains low for one cycle even if the decode phase of the IACK instruction is extended.





SGUS039 - AUGUST 2002

### serial-port timing (see Figure 22 and Figure 23)

NO.				MIN	MAX	UNIT		
54	<sup>t</sup> d(H1H-SCK)	Delay time, H1 high to internal CLKX/R			13	ns		
			CLKX/R ext	t <sub>c(H)</sub> x2.6				
55	<sup>t</sup> c(SCK)	Cycle time, CLKX/R	CLKX/R int	t <sub>c(H)</sub> x2	t <sub>c(H)</sub> x2 <sup>32</sup>	ns		
50			CLKX/R ext	t <sub>c(H)</sub> +10				
56	<sup>t</sup> w(SCK)	Pulse duration, CLKX/R high/low	CLKX/R int	[t <sub>c(SCK)</sub> /2]-5	[t <sub>c(SCK)</sub> /2]+5	ns		
57	tr(SCK)	Rise time, CLKX/R		· ·	7	ns		
58	<sup>t</sup> f(SCK)	Fall time, CLKX/R			7	ns		
59		Deleviting OLICY to DY velicit	CLKX ext		30			
	<sup>t</sup> d(C-DX)	<sup>t</sup> d(C-DX)	Delay time, CLKX to DX valid	CLKX int		17	ns	
			CLKR ext	9				
60	<sup>t</sup> su(DR-CLKRL)	Setup time, DR before CLKR low	CLKR int	21		ns		
			CLKR ext	9				
61	<sup>t</sup> h(CLKRL-DR)	CLKRL-DR) Hold time, DR from CLKR low	CLKR int	0		ns		
			CLKX ext		27			
62	<sup>t</sup> d(C-FSX)	Delay time, CLKX to internal FSX high/low	CLKX int		15	ns		
					CLKR ext	9		
63	<sup>t</sup> su(FSR-CLKRL)	Setup time, FSR before CLKR low	CLKR int	9		ns		
			CLKX/R ext	9				
64	<sup>t</sup> h(SCKL-FS)	Hold time, FSX/R input from CLKX/R low	CLKX/R int	0		ns		
			CLKX ext	-[t <sub>c(H)</sub> -8]*	[t <sub>c(SCK)</sub> /2]-10*			
65	<sup>t</sup> su(FSX-C)	Setup time, external FSX before CLKX	CLKX int	[t <sub>c(H)</sub> -21]*	tc(SCK)/2*	ns		
00		Delay time, CLKX to first DX bit, FSX	CLKX ext		30*			
66	<sup>t</sup> d(CH-DX)V	precedes CLKX high	CLKX int		18*	ns		
67	<sup>t</sup> d(FSX-DX)V	Delay time, FSX to first DX bit, CLKX precede	es FSX		30*	ns		
68	<sup>t</sup> d(CH-DXZ)	Delay time, CLKX high to DX high impedance bit		17*	ns			

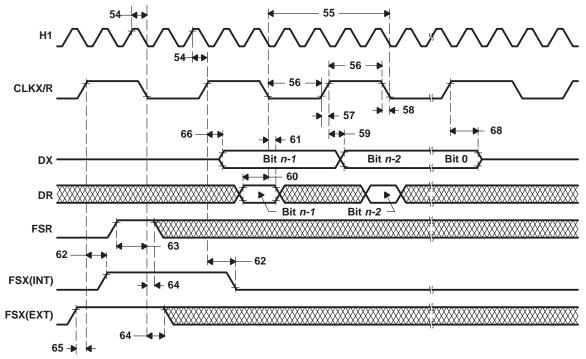
\* This parameter is not production tested.



SGUS039 - AUGUST 2002

#### data-rate timing modes

Unless otherwise indicated, the data-rate timings shown in Figure 22 and Figure 23 are valid for all serial-port modes, including handshake. For a functional description of serial-port operation, see the *TMS320C3x User's Guide* (literature number SPRU031).



NOTES: A. Timing diagrams show operations with CLKXP = CLKRP = FSXP = FSRP = 0.

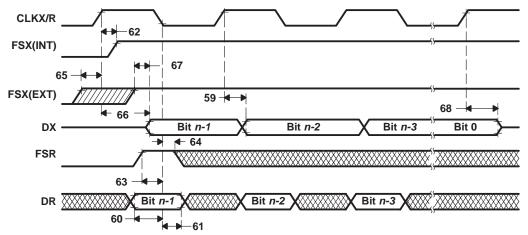
B. Timing diagrams depend on the length of the serial-port word, where n = 8, 16, 24, or 32 bits, respectively.

Figure 22. Timing for Fixed Data-Rate Mode



SGUS039 - AUGUST 2002

#### data-rate timing modes (continued)



- NOTES: A. Timing diagrams show operation with CLKXP = CLKRP = FSXP = FSRP = 0.
  - B. Timing diagrams depend on the length of the serial-port word, where n = 8, 16, 24, or 32 bits, respectively.
  - C. The timings that are not specified expressly for the variable data-rate mode are the same as those that are specified for the fixed data-rate mode.





#### **HOLD** timing

HOLD is an asynchronous input that can be asserted at any time during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 27 occurs; otherwise, an additional delay of one clock cycle is possible.

The NOHOLD bit of the primary-bus control register overrides the HOLD signal. When this bit is set, the device comes out of hold and prevents future hold cycles.

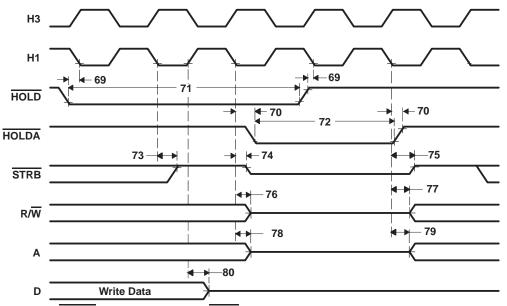
Asserting HOLD prevents the processor from accessing the primary bus. Program execution continues until a read from or a write to the primary bus is requested. In certain circumstances, the first write is pending, thus allowing the processor to continue until a second write is encountered.

NO.			MIN	MAX	UNIT
69	<sup>t</sup> su(HOLD-H1L)	Setup time, HOLD before H1 low	13		ns
70	<sup>t</sup> v(H1L-HOLDA)	Valid time, HOLDA after H1 low	0*	9	ns
71	<sup>t</sup> w(HOLD) <sup>†</sup>	Pulse duration, HOLD low	2t <sub>c(H)</sub>		ns
72	<sup>t</sup> w(HOLDA)	Pulse duration, HOLDA low	t <sub>cH</sub> −5*		ns
73	<sup>t</sup> d(H1L-SH)H	Delay time, H1 low to STRB high for a HOLD	0*	9	ns
74	<sup>t</sup> dis(H1L-S)	Disable time, H1 low to STRB to the high-impedance state	0*	9*	ns
75	<sup>t</sup> en(H1L-S)	Enable time, H1 low to STRB enabled (active)	0*	9	ns
76	<sup>t</sup> dis(H1L-RW)	Disable time, H1 low to $R/\overline{W}$ to the high-impedance state	0*	9*	ns
77	<sup>t</sup> en(H1L-RW)	Enable time, H1 low to $R/\overline{W}$ enabled (active)	0*	9	ns
78	<sup>t</sup> dis(H1L-A)	Disable time, H1 low to address to the high-impedance state	0*	10*	ns
79	<sup>t</sup> en(H1L-A)	Enable time, H1 low to address enabled (valid)	0*	13	ns
80	<sup>t</sup> dis(H1H-D)	Disable time, H1 high to data to the high-impedance state	0*	9*	ns

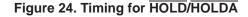
#### timing for HOLD/HOLDA (see Figure 24)

<sup>†</sup> HOLD is an asynchronous input and can be asserted at any point during a clock cycle. If the specified timings are met, the exact sequence shown in Figure 24 occurs; otherwise, an additional delay of one clock cycle is possible.

\* This parameter is not production tested.



NOTE A: HOLDA goes low in response to HOLD going low and continues to remain low until one H1 cycle after HOLD goes back high.





#### SUS039 - AUGUST 2002

#### general-purpose I/O timing

Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The contents of the internal control registers associated with each peripheral define the modes for these pins.

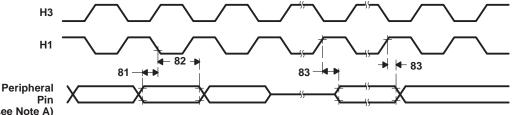
#### peripheral pin I/O timing

The table, timing parameters for peripheral pin general-purpose I/O, defines peripheral pin general-purpose I/O timing parameters.

#### timing requirements for peripheral pin general-purpose I/O (see Note 6 and Figure 25)

NO.		MIN	MAX	UNIT
81	t <sub>su(GPIO-H1L)</sub> Setup time, general-purpose input before H1 low	10		ns
82	th(H1L-GPIO) Hold time, general-purpose input after H1 low	0		ns
83	t <sub>d(H1H-GPIO)</sub> Delay time, general-purpose output after H1 high		13	ns

NOTE 6: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.



(see Note A)

NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

#### Figure 25. Timing for Peripheral Pin General-Purpose I/O



SUS039 - AUGUST 2002

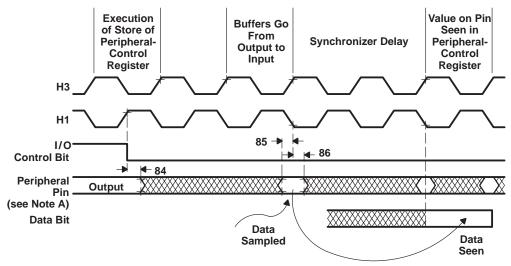
#### changing the peripheral pin I/O modes

The following tables show the timing parameters for changing the peripheral pin from a general-purpose output pin to a general-purpose input pin and vice versa.

# timing requirements for peripheral pin changing from general-purpose output to input mode (see Note 6 and Figure 26)

NO.		MIN MAX	UNIT
84	th(H1H) Hold time, peripheral pin after H1 high	13	ns
85	t <sub>su(GPIO-H1L)</sub> Setup time, peripheral pin before H1 low	9	ns
86	th(H1L-GPIO) Hold time, peripheral pin after H1 low	0	ns

NOTE 6: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.



NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

Figure 26. Timing for Change of Peripheral Pin From General-Purpose Output to Input Mode

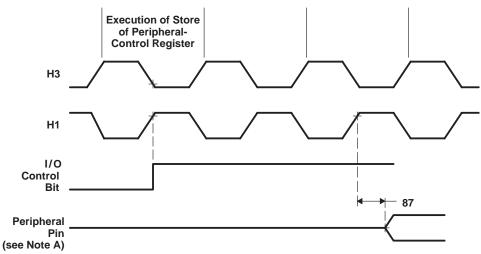


SUS039 - AUGUST 2002

# timing for peripheral pin changing from general-purpose input to output mode (see Note 6 and Figure 27)

NO.		MIN	MAX	UNIT		
87	t <sub>d</sub> (H1H-GPIO) Delay time, H1 high to peripheral pin switching from input to output		13	ns		
NOTE 6: Parinhard ning include CLKY0 CLKP0 DY0 DP0 ESY0 ESP0 and TCLK0/1. The medag of these ning are defined by the contents						

NOTE 6: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1. The modes of these pins are defined by the contents of internal-control registers associated with each peripheral.



NOTE A: Peripheral pins include CLKX0, CLKR0, DX0, DR0, FSX0, FSR0, and TCLK0/1.

Figure 27. Timing for Change of Peripheral Pin From General-Purpose Input to Output Mode



SUS039 - AUGUST 2002

#### timer pin timing

Valid logic-level periods and polarity are specified by the contents of the internal control registers.

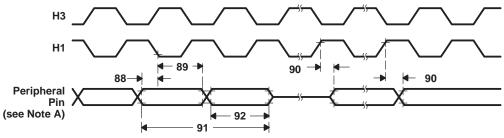
The following tables define the timing requirements for the timer pin.

#### timing for timer pin (see Note 7 and Figure 28)

NO.				MIN	MAX	UNIT
88	tsu(TCLK-H1L)	Setup time, TCLK external before H1 low		10		ns
89	<sup>t</sup> h(H1L-TCLK)	Hold time, TCLK external after H1 low		0		ns
90	<sup>t</sup> d(H1H-TCLK)	Delay time, H1 high to TCLK internal valid			9	ns
04	to/TCLK) Cycle time, TCLK		TCLK ext	t <sub>c(H)</sub> ×2.6		
91		TCLK int	t <sub>c(H)</sub> ×2	t <sub>c(H)</sub> ×232*	ns	
92	tw(TCLK) Pulse duration, TCLK high/low		TCLK ext	<sup>t</sup> c(H)+10		ns
92			TCLK int	[t <sub>c(TCLK)</sub> /2]-5	[t <sub>c(TCLK)</sub> /2]+5	115

\* This parameter is not production tested.

NOTE 7: Numbers 88 and 89 are applicable for a synchronous input clock. Timing parameters 91 and 92 are applicable for an asynchronous input clock.



NOTE A: HOLDA goes low in response to HOLD going low and continues to remain low until one H1 cycle after HOLD goes back high.

Figure 28. Timing for Timer Pin



SUS039 - AUGUST 2002

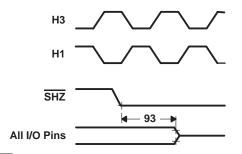
#### SHZ pin timing

The following table defines the timing parameter for the  $\overline{SHZ}$  pin.

## timing parameters for SHZ (see Figure 29)

NO.		MIN	MAX	UNIT
93	tdis(SHZ) Disable time, SHZ low to all O, I/O pins disabled (high impedance)	0*	2P†*	ns
+ -		-		

<sup>†</sup>  $P = t_{C(CI)}$ \* This parameter is not production tested.



NOTE A: Enabling SHZ destroys SM320LC31-EP register and memory contents. Assert SHZ = 1 and reset the SM320LC31-EP to restore it to a known condition.





SGUS039 - AUGUST 2002

#### PROCESSING POWER OPERATING DEVICE TECHNOLOGY PACKAGE TYPE SUPPLY FREQUENCY LEVEL SM320LC31PQM40EP EΡ 0.72-µm CMOS $3.3 V \pm 5\%$ 40 MHz Plastic 132-lead good flatpack SM PQ 320 (L) C 31 Μ 40 EP - ENHANCED PLASTIC PREFIX -SMJ = MIL-PRF-38535 (QML) SM = Standard Processing SMQ = Plastic (QML) SPEED RANGE 40 = 40 MHz50 = 50 MHz DEVICE FAMILY 60 = 60 MHz320 = SMJ320 Family **TEMPERATURE RANGE** TECHNOLOGY $M = -55^{\circ}C \text{ to } 125^{\circ}C$ $S = -55^{\circ}C \text{ to } 105^{\circ}C$ $L = 0^{\circ}C \text{ to } 70^{\circ}C$ L = Low Voltage (3.3-V option) PACKAGE TYPE TECHNOLOGY GFA = 141-Pin Ceramic Staggered Pin Grid C = CMOSArray Ceramic Package HFG = 132-Pin Ceramic Quad Flatpack with a DEVICE nonconductive tie bar PQ 132-lead Plastic Quad Flatpack 31 = 320C31 or 320LC31 = = 132-lead TAB frame with TA polyimide encapsulant ТΒ 132-lead TAB frame, bare-die = option KGD = Known Good Die

part order information

Note: Not all speed, package, process, or temperature combinations are available.

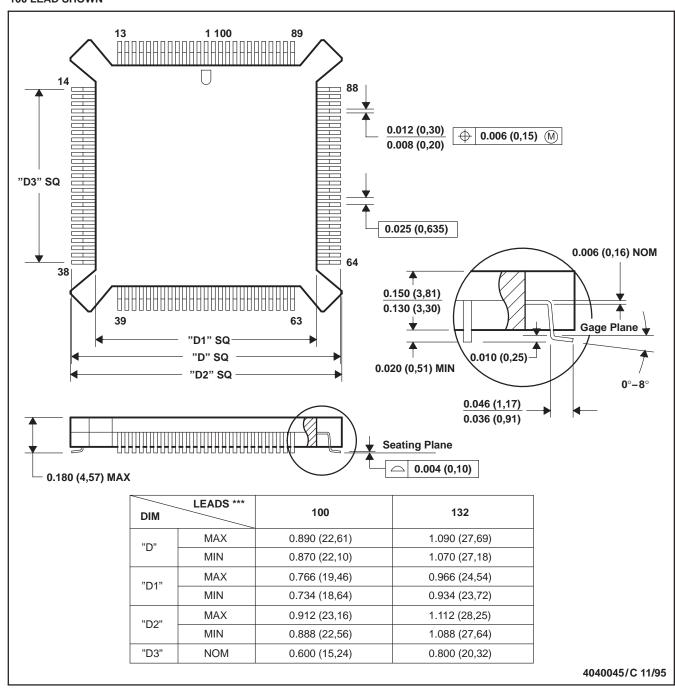
Figure 30. Device Nomenclature



SGUS039 - AUGUST 2002

**MECHANICAL DATA** 

PQ (S-PQFP-G\*\*\*) 100 LEAD SHOWN PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MO-069



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